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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/659,006	09/09/2003	Christopher H. Bajorek	004085.P030X	3505

7590 10/02/2006

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EXAMINER

DANIELS, MATTHEW J

ART UNIT	PAPER NUMBER
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1732

DATE MAILED: 10/02/2006

Please find below and/or attached an Office communication concerning this application or proceeding.

Interview Summary

Application No.

10/659,006

Applicant(s)

BAJOREK, CHRISTOPHER
H.

Examiner

Matthew J. Daniels

Art Unit

1732

All participants (applicant, applicant's representative, PTO personnel):

(1) Matthew J. Daniels.

(3) _____.

(2) Daniel Ovanezian.

(4) _____.

Date of Interview: 27 September 2006.

Type: a) ☒ Telephonic b) ☐ Video Conference
c) ☐ Personal [copy given to: 1) ☐ applicant 2) ☐ applicant's representative]

Exhibit shown or demonstration conducted: d) ☐ Yes e) ☐ No.

If Yes, brief description: _____.

Claim(s) discussed: 1.

Identification of prior art discussed: Davis (US 2005/0025408).


Agreement with respect to the claims f) ☐ was reached. g) ☒ was not reached. h) ☐ N/A.

Substance of Interview including description of the general nature of what was agreed to if an agreement was reached, or any other comments: See Continuation Sheet.

(A fuller description, if necessary, and a copy of the amendments which the examiner agreed would render the claims allowable, if available, must be attached. Also, where no copy of the amendments that would render the claims allowable is available, a summary thereof must be attached.)

THE FORMAL WRITTEN REPLY TO THE LAST OFFICE ACTION MUST INCLUDE THE SUBSTANCE OF THE INTERVIEW. (See MPEP Section 713.04). If a reply to the last Office action has already been filed, APPLICANT IS GIVEN A NON-EXTENDABLE PERIOD OF THE LONGER OF ONE MONTH OR THIRTY DAYS FROM THIS INTERVIEW DATE, OR THE MAILING DATE OF THIS INTERVIEW SUMMARY FORM, WHICHEVER IS LATER, TO FILE A STATEMENT OF THE SUBSTANCE OF THE INTERVIEW. See Summary of Record of Interview requirements on reverse side or on attached sheet.

Examiner Note: You must sign this form unless it is an Attachment to a signed Office action.


Examiner's signature, if required

Summary of Record of Interview Requirements

Manual of Patent Examining Procedure (MPEP), Section 713.04, Substance of Interview Must be Made of Record

A complete written statement as to the substance of any face-to-face, video conference, or telephone interview with regard to an application must be made of record in the application whether or not an agreement with the examiner was reached at the interview.

Title 37 Code of Federal Regulations (CFR) § 1.133 Interviews

Paragraph (b)

In every instance where reconsideration is requested in view of an interview with an examiner, a complete written statement of the reasons presented at the interview as warranting favorable action must be filed by the applicant. An interview does not remove the necessity for reply to Office action as specified in §§ 1.111, 1.135. (35 U.S.C. 132)

37 CFR §1.2 Business to be transacted in writing.

All business with the Patent and Trademark Office should be transacted in writing. The personal attendance of applicants or their attorneys or agents at the Patent and Trademark Office is unnecessary. The action of the Patent and Trademark Office will be based exclusively on the written record in the Office. No attention will be paid to any alleged oral promise, stipulation, or understanding in relation to which there is disagreement or doubt.

The action of the Patent and Trademark Office cannot be based exclusively on the written record in the Office if that record is itself incomplete through the failure to record the substance of interviews.

It is the responsibility of the applicant or the attorney or agent to make the substance of an interview of record in the application file, unless the examiner indicates he or she will do so. It is the examiner's responsibility to see that such a record is made and to correct material inaccuracies which bear directly on the question of patentability.

Examiners must complete an Interview Summary Form for each interview held where a matter of substance has been discussed during the interview by checking the appropriate boxes and filling in the blanks. Discussions regarding only procedural matters, directed solely to restriction requirements for which interview recordation is otherwise provided for in Section 812.01 of the Manual of Patent Examining Procedure, or pointing out typographical errors or unreadable script in Office actions or the like, are excluded from the interview recordation procedures below. Where the substance of an interview is completely recorded in an Examiners Amendment, no separate Interview Summary Record is required.

The Interview Summary Form shall be given an appropriate Paper No., placed in the right hand portion of the file, and listed on the "Contents" section of the file wrapper. In a personal interview, a duplicate of the Form is given to the applicant (or attorney or agent) at the conclusion of the interview. In the case of a telephone or video-conference interview, the copy is mailed to the applicant's correspondence address either with or prior to the next official communication. If additional correspondence from the examiner is not likely before an allowance or if other circumstances dictate, the Form should be mailed promptly after the interview rather than with the next official communication.

The Form provides for recordation of the following information:

- Application Number (Series Code and Serial Number)
- Name of applicant
- Name of examiner
- Date of interview
- Type of interview (telephonic, video-conference, or personal)
- Name of participant(s) (applicant, attorney or agent, examiner, other PTO personnel, etc.)
- An indication whether or not an exhibit was shown or a demonstration conducted
- An identification of the specific prior art discussed
- An indication whether an agreement was reached and if so, a description of the general nature of the agreement (may be by attachment of a copy of amendments or claims agreed as being allowable). Note: Agreement as to allowability is tentative and does not restrict further action by the examiner to the contrary.
- The signature of the examiner who conducted the interview (if Form is not an attachment to a signed Office action)

It is desirable that the examiner orally remind the applicant of his or her obligation to record the substance of the interview of each case. It should be noted, however, that the Interview Summary Form will not normally be considered a complete and proper recordation of the interview unless it includes, or is supplemented by the applicant or the examiner to include, all of the applicable items required below concerning the substance of the interview.

A complete and proper recordation of the substance of any interview should include at least the following applicable items:

- 1) A brief description of the nature of any exhibit shown or any demonstration conducted,
- 2) an identification of the claims discussed,
- 3) an identification of the specific prior art discussed,
- 4) an identification of the principal proposed amendments of a substantive nature discussed, unless these are already described on the Interview Summary Form completed by the Examiner,
- 5) a brief identification of the general thrust of the principal arguments presented to the examiner,
(The identification of arguments need not be lengthy or elaborate. A verbatim or highly detailed description of the arguments is not required. The identification of the arguments is sufficient if the general nature or thrust of the principal arguments made to the examiner can be understood in the context of the application file. Of course, the applicant may desire to emphasize and fully describe those arguments which he or she feels were or might be persuasive to the examiner.)
- 6) a general indication of any other pertinent matters discussed, and
- 7) if appropriate, the general results or outcome of the interview unless already described in the Interview Summary Form completed by the examiner.

Examiners are expected to carefully review the applicant's record of the substance of an interview. If the record is not complete and accurate, the examiner will give the applicant an extendable one month time period to correct the record.

Examiner to Check for Accuracy

If the claims are allowable for other reasons of record, the examiner should send a letter setting forth the examiner's version of the statement attributed to him or her. If the record is complete and accurate, the examiner should place the indication, "Interview Record OK" on the paper recording the substance of the interview along with the date and the examiner's initials.

Continuation of Substance of Interview including description of the general nature of what was agreed to if an agreement was reached, or any other comments: Applicant's counsel provided the enclosed claim amendments for discussion. First, the Examiner argued that the word "substantial" would likely result in a rejection under 35 USC 112, second paragraph as being indefinite. Additionally, Applicant's counsel pointed to the last sentence of paragraph [0075] for teaching of typically cooling the molded substrate prior to removal of the mold. The Examiner responded that the remainder of paragraph [0075] teaches that temperature is a result effective variable that should be optimized. The Examiner asserted that of the two teachings, the Examiner's interpretation is the broadest reasonable interpretation, and reads on the claim.

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IN THE CLAIMS

1. (Currently Amended) A method, comprising:
heating a stamper and a resist film;
imprinting the stamper into the resist film;
separating the stamper from the resist film before there is any substantial cooling of the resist film before the separation; and
cooling the resist film after separating.
 2. (Original) The method of claim 1, wherein the stamper and the resist film are heated to a temperature at least that of a glass transition temperature of the resist film.
 3. (Original) The method of claim 1, wherein imprinting the stamper into the resist film comprises imprinting the stamper into the resist film to produce a pattern of trenches areas and plateau areas.
 4. (Original) The method of claim 1, further comprising disposing the resist film above a base structure prior to the heating, wherein the base structure comprises a substrate.
 5. (Original) The method of claim 4, further comprising selectively removing the resist film to form a pattern of areas above the base structure that do not have the resist film thereon.
 6. (Original) The method of claim 5, further comprising disposing a magnetic layer above the base structure in the areas that do not have the resist film.
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7. (Original) The method of claim 5, further comprising etching the base structure using the patterned resist film.
8. (Original) The method of claim 1, wherein the resist film comprises a single resist layer.
9. (Original) The method of claim 1, wherein the resist film comprises a plurality of resist layers.
10. (Original) The method of claim 2, further comprising preheating the resist film to the temperature.
11. (Original) The method of claim 1, wherein heating the stamper and the resist film comprises separately heating the stamper and the resist film.
12. (Original) The method of claim 11, wherein the stamper and the resist film are separately heated to an imprint temperature at least that of a glass transition temperature of the resist film.
13. (Original) The method of claim 12, further comprising placing the resist film in close proximity to the stamper while the resist film is approximately at the imprint temperature.

14. (Original) The method of claim 11, wherein the stamper is heated to a first temperature at least that of a glass transition temperature of the resist film and wherein the resist film is separately heated to a second temperature below that of the first temperature.

15. (Original) The method of claim 14, further comprising further heating the resist film to the first temperature.

16. (Original) The method of claim 11, wherein the stamper is heated to a first temperature at least that of a glass transition temperature of the resist film and wherein the resist film is separately heated to a second temperature above that of the first temperature.

17. (Original) A method, comprising:
heating a stamper and a resist film to a first temperature at least that of a transition temperature of the resist film;
imprinting the stamper into the resist film;
cooling the resist film to a second temperature above room temperature; and
separating the stamper from the resist film.

18. (Original) The method of claim 17, further comprising disposing the resist film above a base structure prior to the heating, wherein the base structure comprises a substrate.

19. (Original) The method of claim 17, further comprising:

selectively etching the resist film to form a pattern of areas above the base structure that do not have the resist film thereon; and

disposing a magnetic layer above the base structure in the areas that do not have the resist film.

20. (Original) The method of claim 17, wherein the resist film comprises a single resist layer.

21. (Original) The method of claim 17, wherein the resist film comprises a plurality of resist layers.

22. (Previously Presented) The method of claim 1, wherein the resist film comprises a thermosetting material.

23. (Previously Presented) The method of claim 7, further comprising removing the resist film, wherein a pattern of raised zones and recessed zones is formed in the base structure and wherein the method further comprising depositing a continuous film on the pattern of raised zones and recessed zones.

24. (Previously Presented) The method of claim 23, wherein the resist film comprises a thermosetting material.

REMARKS

Applicant respectfully requests reconsideration of this application as amended.

If there are any additional charges, please charge our Deposit Account No. 02-2666.

Respectfully submitted,

BLAKELY, SOKOLOFF, TAYLOR & ZAFMAN LLP

Dated: _____, 2006

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